N-channel dual-gate MOS-FET | BF904WR

FEATURES

- Specially designed for use at 5 V supply voltage
- Short channel transistor with high forward transfer admittance to input capacitance ratio
- Low noise gain controlled amplifier up to 1 GHz
- Superior cross-modulation performance during AGC.

APPLICATIONS

- VHF and UHF applications with 3 to 7 V supply voltage such as television tuners and professional communications equipment.

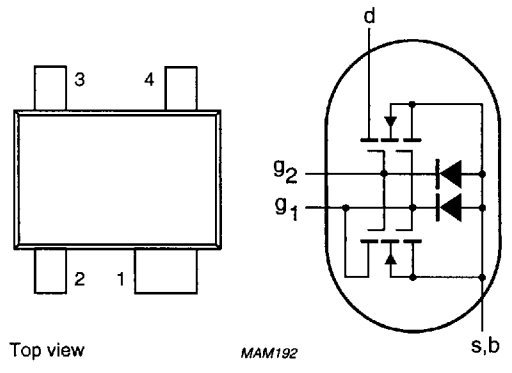
DESCRIPTION

Enhancement type field-effect transistor in a plastic microminiature SOT343R package. The transistor consists of an amplifier MOS-FET with source and substrate interconnected and an internal bias circuit to ensure good cross-modulation performance during AGC.

CAUTION
The device is supplied in an antistatic package. The gate-source input must be protected against static discharge during transport or handling.

PINNING

PIN	SYMBOL	DESCRIPTION
1	s, b	source
2	d	drain
3	g_2	gate 2
4	g_1	gate 1



Marking code: MC.

Fig.1 Simplified outline (SOT343R) and symbol.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{DS}	drain-source voltage		–	–	7	V
I_D	drain current		–	–	30	mA
P_{tot}	total power dissipation		–	–	280	mW
T_j	operating junction temperature		–	–	150	°C
$\lvert y_{fs} \rvert$	forward transfer admittance		22	25	30	mS
$C_{ig1\text{-}s}$	input capacitance at gate 1		–	2.2	2.6	pF
C_{rs}	reverse transfer capacitance	f = 1 MHz	–	25	35	fF
F	noise figure	f = 800 MHz	–	2	–	dB

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage		–	7	V
I_D	drain current		–	30	mA
I_{G1}	gate 1 current		–	±10	mA
I_{G2}	gate 2 current		–	±10	mA
P_{tot}	total power dissipation	up to T_{amb} = 50 °C; see Fig.2; note 1	–	280	mW
T_{stg}	storage temperature		–65	+150	°C
T_j	operating junction temperature		–	+150	°C

Note

1. Device mounted on a printed-circuit board.

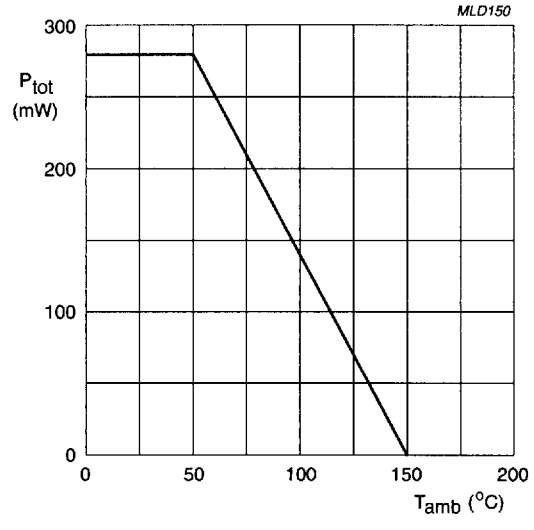


Fig.2 Power derating curve.

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th\ j\text{-}a}$	thermal resistance from junction to ambient	note 1	350	K/W
$R_{th\ j\text{-}s}$	thermal resistance from junction to soldering point	T_s = 91 °C; note 2	210	K/W

Notes

1. Device mounted on a printed-circuit board.
2. T_s is the temperature at the soldering point of the source lead.

STATIC CHARACTERISTICS

T_j = 25 °C; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)G1\text{-}SS}$	gate 1-source breakdown voltage	$V_{G2\text{-}S} = V_{DS} = 0$; $I_{G1\text{-}S}$ = 10 mA	6	15	V
$V_{(BR)G2\text{-}SS}$	gate 2-source breakdown voltage	$V_{G1\text{-}S} = V_{DS} = 0$; $I_{G2\text{-}S}$ = 10 mA	6	15	V
$V_{(F)S\text{-}G1}$	forward source-gate 1 voltage	$V_{G2\text{-}S} = V_{DS} = 0$; $I_{S\text{-}G1}$ = 10 mA	0.5	1.5	V
$V_{(F)S\text{-}G2}$	forward source-gate 2 voltage	$V_{G1\text{-}S} = V_{DS} = 0$; $I_{S\text{-}G2}$ = 10 mA	0.5	1.5	V
$V_{G1\text{-}S(th)}$	gate 1-source threshold voltage	$V_{G2\text{-}S}$ = 4V; V_{DS} = 5 V; I_D = 20 µA	0.3	1	V
$V_{G2\text{-}S(th)}$	gate 2-source threshold voltage	$V_{G1\text{-}S} = V_{DS}$ = 5 V; I_D = 20 µA	0.3	1.2	V
I_{DSX}	drain-source current	$V_{G2\text{-}S}$ = 4 V; V_{DS} = 5 V; R_{G1} = 120 kΩ; note 1	8	13	mA
$I_{G1\text{-}SS}$	gate 1 cut-off current	$V_{G2\text{-}S} = V_{DS} = 0$; $V_{G1\text{-}S}$ = 5 V	–	50	nA
$I_{G2\text{-}SS}$	gate 2 cut-off current	$V_{G1\text{-}S} = V_{DS} = 0$; $V_{G2\text{-}S}$ = 5 V	–	50	nA

Note

1. R_G connects gate 1 to V_{GG} = 5 V.

DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; I_D = 10 mA; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$\lvert y_{fs} \rvert$	forward transfer admittance	pulsed; T_j = 25 °C	22	25	30	mS
$C_{ig1\text{-}s}$	input capacitance at gate 1	f = 1 MHz	–	2.2	2.6	pF
$C_{ig2\text{-}s}$	input capacitance at gate 2	f = 1 MHz	1	1.5	2	pF
C_{os}	drain-source capacitance	f = 1 MHz	1	1.3	1.6	pF
C_{rs}	reverse transfer capacitance	f = 1 MHz	–	25	35	fF
F	noise figure	f = 200 MHz; G_S = 2 mS; $B_S = B_{Sopt}$	–	1	1.5	dB
		f = 800 MHz; $G_S = G_{Sopt}$; $B_S = B_{Sopt}$	–	2	2.8	dB

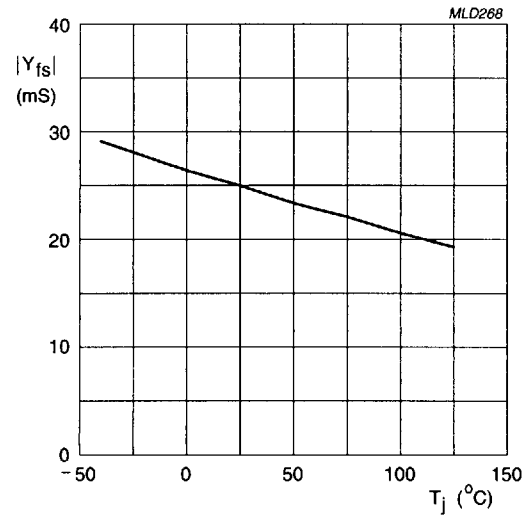
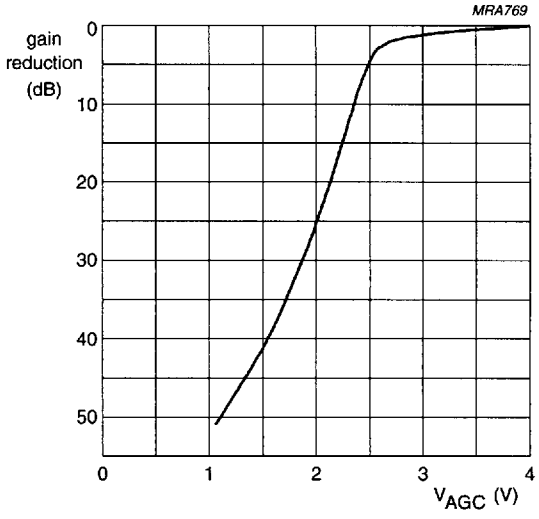
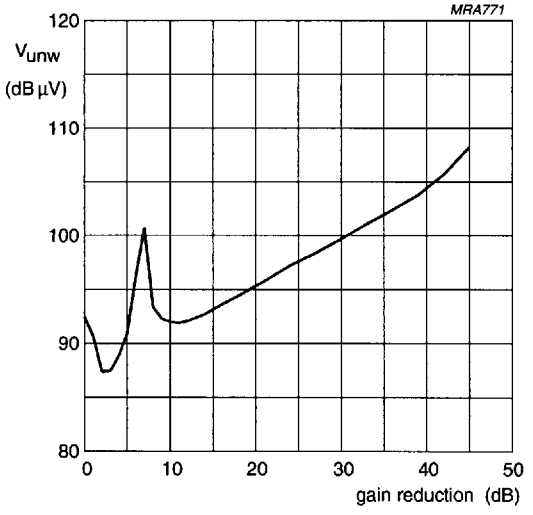


Fig.3 Forward transfer admittance as a function of junction temperature; typical values.



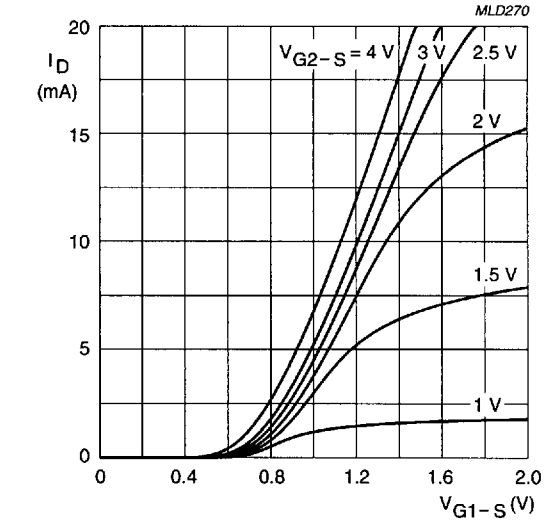
f = 50 MHz.
T_j = 25 °C.

Fig.4 Typical gain reduction as a function of AGC voltage.



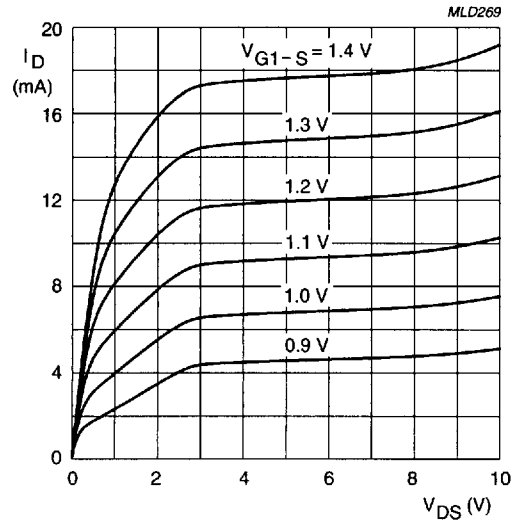
V_{GG} = 5 V; f_w = 50 MHz.
f_{unw} = 60 MHz; T_{amb} = 25 °C; R_{G1} = 120 kΩ.

Fig.5 Unwanted voltage for 1% cross-modulation as a function of gain reduction; typical values; see Fig.19.



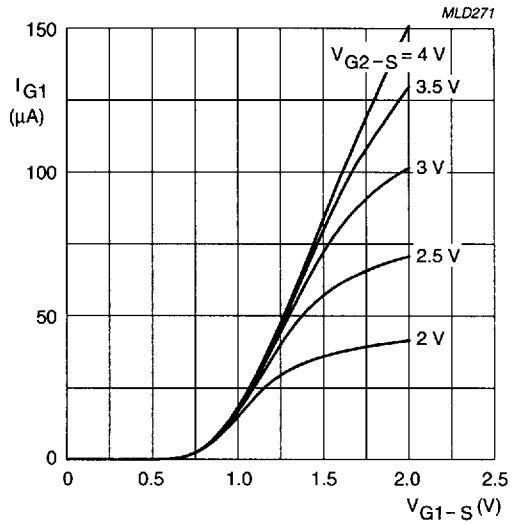
V_{DS} = 5 V.
T_j = 25 °C.

Fig.6 Transfer characteristics; typical values.



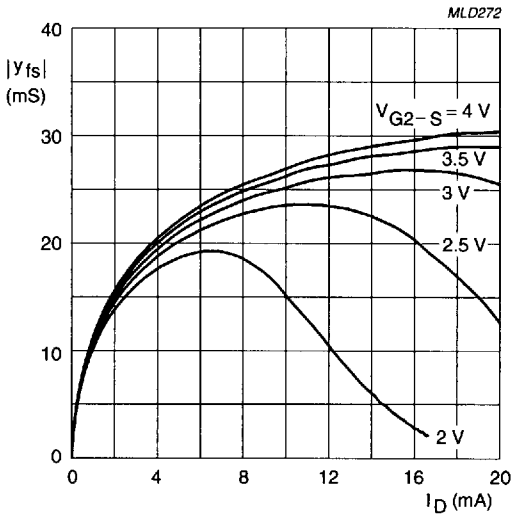
V_{G2-S} = 4 V.
T_j = 25 °C.

Fig.7 Output characteristics; typical values.



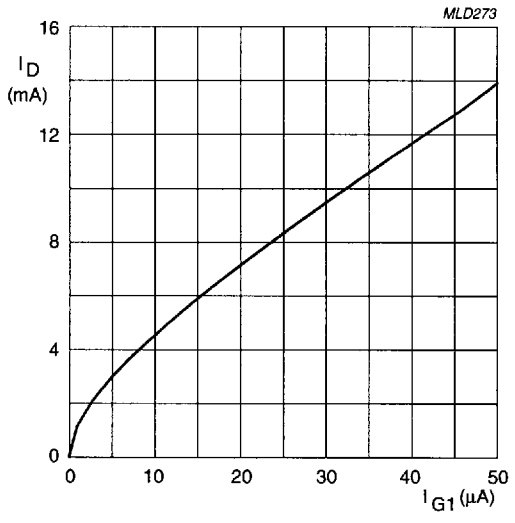
V_{DS} = 5 V.
T_j = 25 °C.

Fig.8 Gate 1 current as a function of gate 1 voltage; typical values.



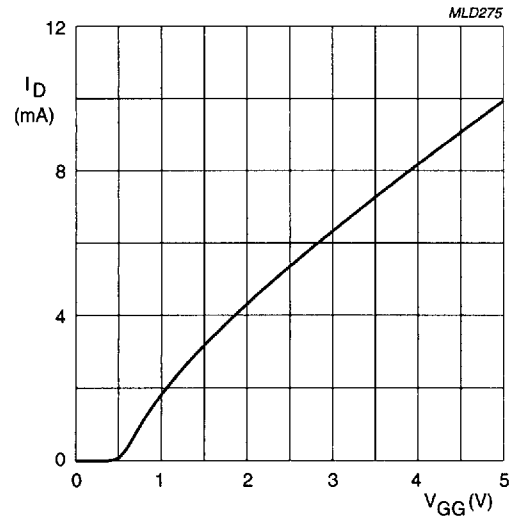
V_{DS} = 5 V.
T_j = 25 °C.

Fig.9 Forward transfer admittance as a function of drain current; typical values.



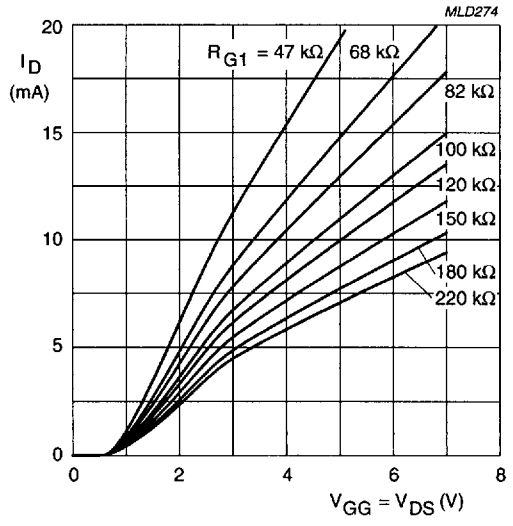
V_{DS} = 5 V; V_{G2-S} = 4 V.
T_j = 25 °C.

Fig.10 Drain current as a function of gate 1 current; typical values.



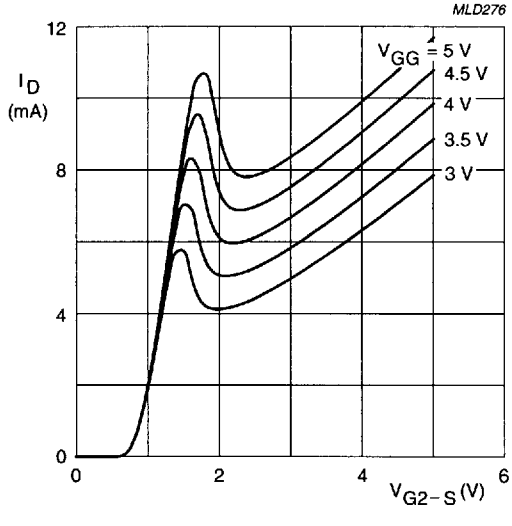
V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V.
R_{G1} = 120 kΩ (connected to V_{GG}); T_j = 25 °C.

Fig.11 Drain current as a function of gate 1 supply voltage (= V_{GG}); typical values; see Fig.19.



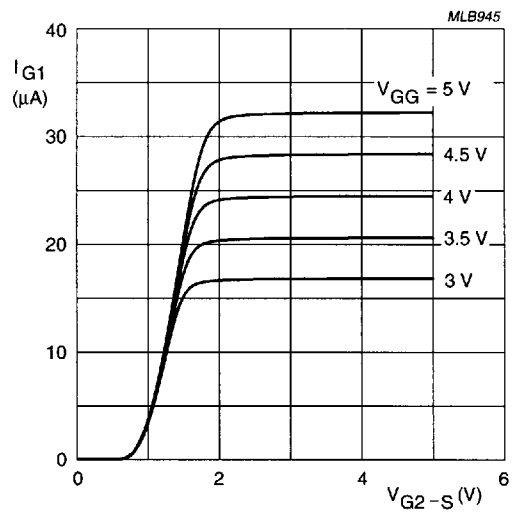
$V_{G2\text{-}S}$ = 4 V.
R_{G1} connected to V_{GG}; T_j = 25 °C.

Fig.12 Drain current as a function of gate 1 (= V_{GG}) and drain supply voltage; typical values; see Fig.19.



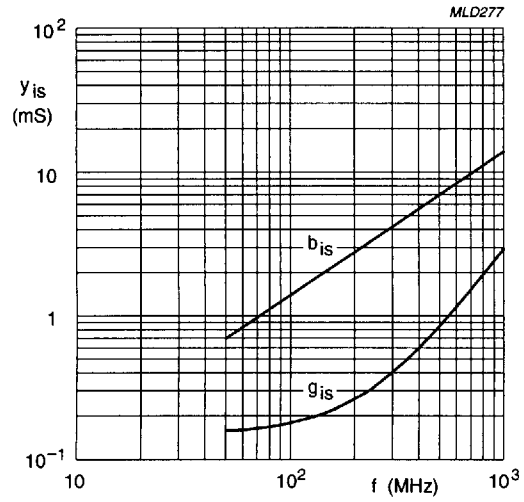
V_{DS} = 5 V; T_j = 25 °C.
R_G = 120 kΩ (connected to V_{GG}).

Fig.13 Drain current as a function of gate 2 voltage; typical values; see Fig.19.



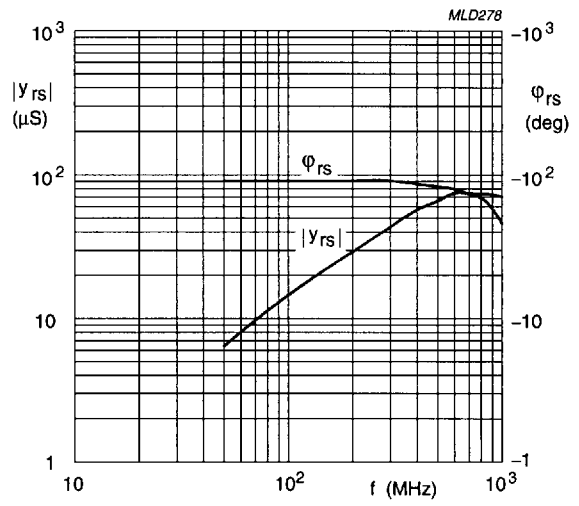
V_{DS} = 5 V; T_j = 25 °C.
R_G = 120 kΩ (connected to V_{GG}).

Fig.14 Gate 1 current as a function of gate 2 voltage; typical values; see Fig.19.



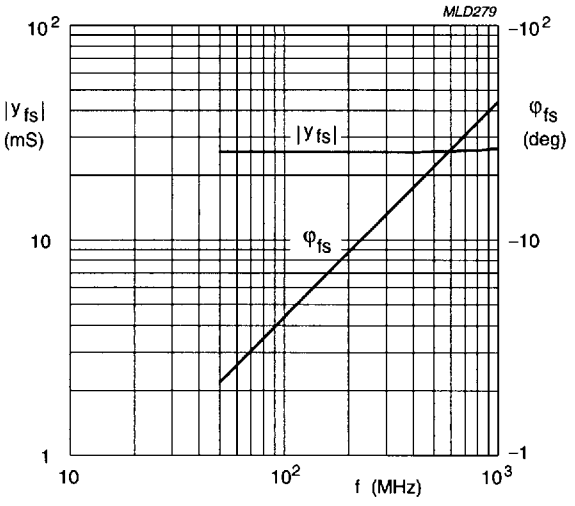
V_{DS} = 5 V; V_{G2} = 4 V.
I_D = 10 mA; T_{amb} = 25 °C.

Fig.15 Input admittance as a function of frequency; typical values.



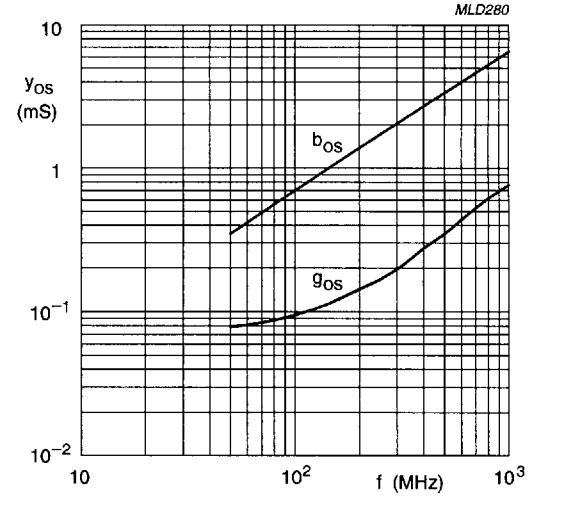
V_{DS} = 5 V; V_{G2} = 4 V.
I_D =10 mA; T_{amb} = 25 °C.

Fig.16 Reverse transfer admittance and phase as a function of frequency; typical values.



V_{DS} = 5 V; V_{G2} = 4 V.
I_D = 10 mA; T_{amb} = 25 °C.

Fig.17 Forward transfer admittance and phase as a function of frequency; typical values.



V_{DS} = 5 V; V_{G2} = 4 V.
I_D = 10 mA; T_{amb} = 25 °C.

Fig.18 Output admittance as a function of frequency; typical values.

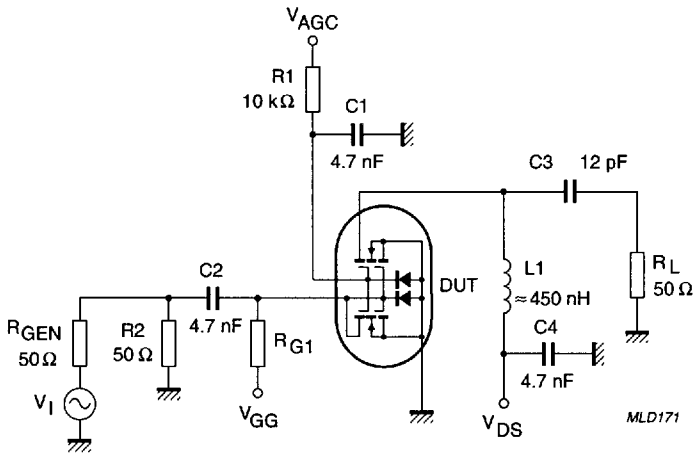


Fig.19 Cross-modulation test set-up.

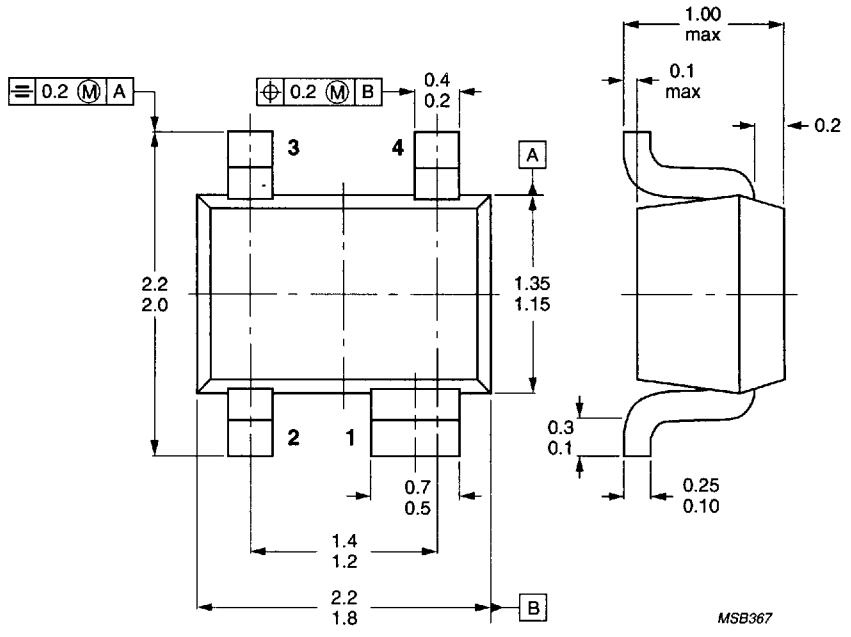
Table 1 Scattering parameters: V_{DS} =5 V; $V_{G2\text{-}S}$ = 4 V; I_D = 10 mA

f (MHz)	s_{11}		s_{21}		s_{12}		s_{22}	
	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
40	0.989	−3.4	2.420	175.7	0.000	79.9	0.993	−1.6
100	0.985	−8.3	2.414	169.1	0.001	78.3	0.992	−3.9
200	0.976	−16.4	2.368	158.8	0.003	80.3	0.987	−7.8
300	0.958	−24.1	2.301	148.5	0.004	73.7	0.980	−11.4
400	0.942	−32.0	2.251	138.8	0.005	70.7	0.974	−15.2
500	0.918	−39.3	2.170	129.5	0.005	67.2	0.966	−18.7
600	0.899	−46.0	2.080	120.7	0.005	67.8	0.958	−22.2
700	0.876	−52.6	2.001	112.1	0.005	68.6	0.951	−25.5
800	0.852	−58.8	1.924	103.2	0.005	72.9	0.944	−28.9
900	0.823	−64.9	1.829	94.7	0.005	78.7	0.937	−32.1
1000	0.800	−70.9	1.747	86.5	0.005	88.3	0.933	−35.2
1200	0.750	−82.4	1.621	70.7	0.005	120.5	0.928	−41.7
1400	0.719	−92.7	1.535	54.6	0.008	139.8	0.930	−48.4
1600	0.682	−102.5	1.424	39.4	0.010	137.8	0.924	−54.9
1800	0.642	−109.8	1.349	22.5	0.013	156.8	0.928	−62.9
2000	0.602	−116.5	1.283	1.1	0.018	175.1	0.928	−73.1
2200	0.547	−124.9	1.130	−15.1	0.014	172.6	0.887	−81.0
2400	0.596	−128.7	1.018	−49.1	0.040	−163.9	0.837	−95.8
2600	0.682	−132.6	0.979	−79.4	0.077	−164.0	0.778	−109.6
2800	0.771	−142.5	0.804	−116.2	0.120	178.8	0.629	−119.5
3000	0.793	−157.5	0.541	−153.5	0.149	158.3	0.479	−119.9

Table 2 Noise data: V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; I_D = 10 mA

f (MHz)	F_{min} (dB)	Γ_{opt}		r_n
		(ratio)	(deg)	
800	2.00	.686	49.6	50.40

PACKAGE OUTLINE



Dimensions in mm.

Fig.20 SOT343R.